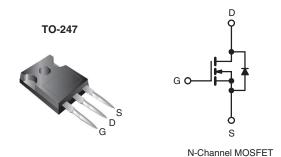


Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	600			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.60		
Q _g (Max.) (nC)	140			
Q _{gs} (nC)	20			
Q _{gd} (nC)	69			
Configuration	Single			



FEATURES

- Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- · Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- · Simple Drive Requirements
- Lead (Pb)-free Available

RoHS*

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole. It also provides greater creepage distance between pins to meet the requirements of most safety specifications.

ORDERING INFORMATION	
Package	TO-247
Lood (Ph) from	IRFPC50PbF
Lead (Pb)-free	SiHFPC50-E3
SnPb	IRFPC50
SIFD	SiHFPC50

PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V_{DS}	600	V	
Gate-Source Voltage	V_{GS}	± 20	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \		
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 ^{\circ}C$	I-	11	А	
	$T_C = 100 ^{\circ}C$	I _D	7.0		
Pulsed Drain Current ^a	I _{DM}	44			
Linear Derating Factor		1.4	W/°C		
Single Pulse Avalanche Energy ^b	E _{AS}	920	mJ		
Repetitive Avalanche Current ^a	I _{AR}	10	Α		
Repetitive Avalanche Energy ^a	E _{AR}	18	mJ		
Maximum Power Dissipation	T _C = 25 °C	P _D	180	W	
Peak Diode Recovery dV/dtc	dV/dt	3.0	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	6-32 OF IVIS SCIEW		1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 13 mH, R_G = 25 Ω , I_{AS} = 11 A (see fig. 12).
- c. $I_{SD} \leq$ 11 A, $dI/dt \leq$ 100 A/ μ s, $V_{DD} \leq$ V_{DS} , $T_{J} \leq$ 150 °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFPC50, SiHFPC50

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THERMAL RESISTANCE					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	-	40	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	-	0.24	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	0.65	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		600	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = 1 mA		0.78	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	· V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 20 V		-	± 100	nA
Zous Cata Valtaga Duais Commant	I _{DSS}	V _{DS} =	V _{DS} = 600 V, V _{GS} = 0 V		-	100	^
Zero Gate Voltage Drain Current		V _{DS} = 480 V	', V _{GS} = 0 V, T _J = 125 °C	-	-	500	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 6.0 A ^b	-	-	0.60	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 100 V, I _D = 6.0 A ^b		5.7	-	-	S
Dynamic							
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	2700	-	pF
Output Capacitance	C _{oss}			-	300	-	
Reverse Transfer Capacitance	C _{rss}			-	61	-	
Total Gate Charge	Qg		$V_{GS} = 10 \text{ V}$ $I_D = 11 \text{ A}, V_{DS} = 360 \text{ V}$ see fig. 6 and 13^b	-	-	140	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	20	
Gate-Drain Charge	Q _{gd}	7		-	-	69	
Turn-On Delay Time	t _{d(on)}		V _{DD} = 300 V, I _D = 11 A,		18	-	- ns
Rise Time	t _r	V _{DD} -			37	-	
Turn-Off Delay Time	t _{d(off)}	$R_{G} = 6.2 \Omega, R_{D} = 30 \Omega, \text{ see fig. } 10^{b}$		-	88	-	
Fall Time	t _f			-	36	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH
Internal Source Inductance	L _S			-	13	-	""
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	11	A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	44	
Body Diode Voltage	V _{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 11 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.4	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 11 A, dl/dt = 100 A/μs ^b		-	550	830	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.9	5.9	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L					

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

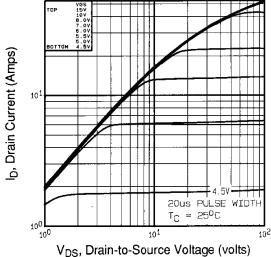
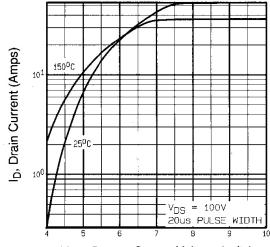


Fig. 1 - Typical Output Characteristics, T_C = 25 °C



V_{GS}, Gate-to-Source Voltage (volts)

Fig. 3 - Typical Transfer Characteristics

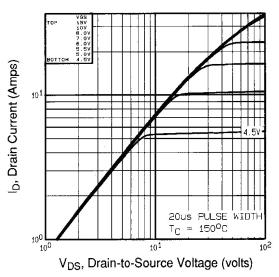


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

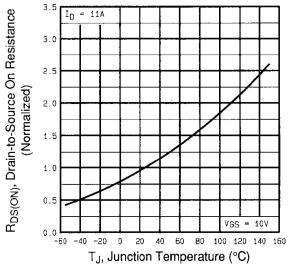


Fig. 4 - Normalized On-Resistance vs. Temperature

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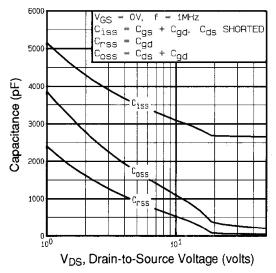


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

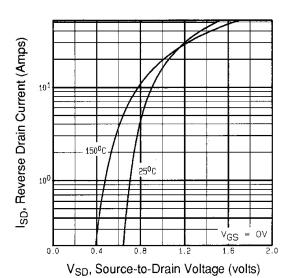


Fig. 7 - Typical Source-Drain Diode Forward Voltage

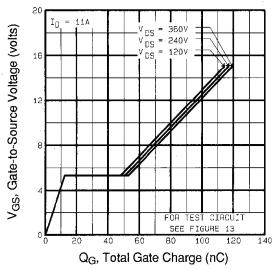


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

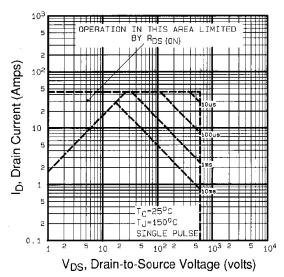


Fig. 8 - Maximum Safe Operating Area





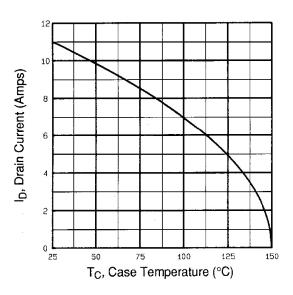


Fig. 9 - Maximum Drain Current vs. Case Temperature

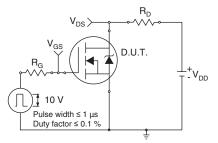


Fig. 10a - Switching Time Test Circuit

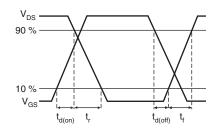


Fig. 10b - Switching Time Waveforms

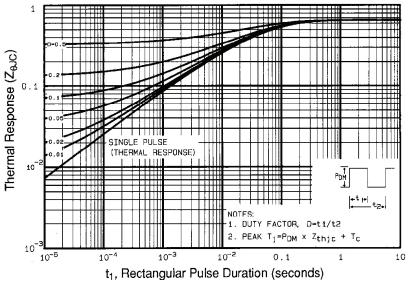
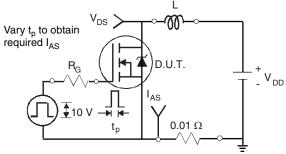


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

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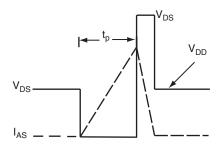


Fig. 12b - Unclamped Inductive Waveforms

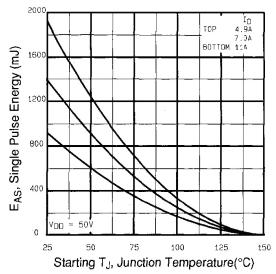


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

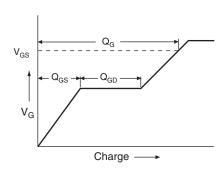


Fig. 13a - Basic Gate Charge Waveform

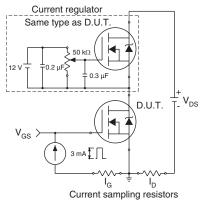
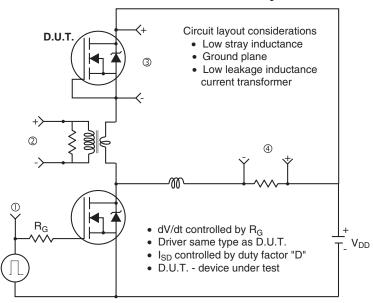
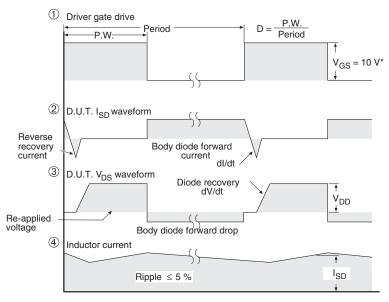


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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